TITLE

| U.S. | UTILITY | Patent Ap | oplication |
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| mT O.I.P.E.        | PATENT DATE |  |
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| APPLICATION NO. | CONT/PRIOR | CLASS   | SUBCLASS - | ART UNIT/256 | EXAMINER | young       |
| 09/986084       | F          | 256 6 2 | 20/2       | 2877         | € 43°    | A125 C      |
|                 |            |         |            | <u> </u>     |          |             |

Shuji Nakao Yuki Miyamoto Naohisa Tamada

Focus monitoring method, focus monitoring apparatus, and method of manufacturing semiconductor device

PTO-2040 12/99 

| ISSUING CLASSIFICATION       |       |  |  |  |  |
|------------------------------|-------|--|--|--|--|
| ORIGINAL CROSS REFERENCE(S)  |       |  |  |  |  |
| CLASS SUBCLASS               | CLASS | SUBCLASS (ONE SUBCLASS PER BLOCK)  |  |  |  |
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| INTERNATIONAL CLASSIFICATION |       |  |  |  |  |
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| TERMINAL  | DRAWINGS   |                   | CLAIMS ALLOWED             |                              |  |
|---|--|-------------------|----------------------------|------------------------------|--|
| L-Joisclaimer   | Sheets Drwg. Figs. Drwg.   | Print Fig.        | Total Claims               | Print Claim for O.G.         |  |
| The term of this patent , subsequent to(date) has been disclaimed.                              | (Assistant Examiner)   | (Date)            | NOTICE OF ALL              | OWANCE MAILED                |  |
| The term of this patent shall not extend beyond the expiration date of U.S Patent. No.          |  |                   | ISSI                       | JE FEE                       |  |
|   | (Primary Examinar)   | (Date)            | Amount Due                 | Date Paid                    |  |
| ☐ The terminalmonths of this patent have been disclaimed.                                       | (Legal tratruments Examiner)   | (Date)            | ISSUE BAT                  | CH NUMBER                    |  |
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